

Search Notes

Application/Control No.

10/532,864

Examiner

Hau V. Phan

Applicant(s)/Patent under
Reexamination

KANO ET AL.

Art Unit

3618

SEARCHED

Class	Subclass	Date	Examiner
180	65.1	12/6/2007	HP
	65.2		
	65.3		
	65.4		
	65.5		
	65.6		
	65.7		
903	951	12/6/2007	HP
	905		
	906		
	911		
475	230	12/6/2007	HP
	231		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR